

Product Change Notification: MAAN-27WMLJ297

Date:

30-Oct-2024

Product Category:

Switching Regulators

Notification Subject:

CCB 7227 Initial Notice: Qualification of ATP7 as an additional assembly site for selected MCP16411, MCP16412, MCP16413, MCP16414, MCP16415, MCP16416, MCP16417 and MCP16418 device families available in 10L TDFN (3x3x0.8mm) package.

Affected CPNs:

MAAN-27WMLJ297_Affected_CPN_10302024.pdf MAAN-27WMLJ297 Affected CPN 10302024.csv

PCN Status: Initial Notification

PCN Type: Manufacturing Change

Microchip Parts Affected: Please open one of the files found in the Affected CPNs section. Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change: Qualification of ATP7 as an additional assembly site for selected MCP16411, MCP16412, MCP16413, MCP16414, MCP16415, MCP16416, MCP16417 and MCP16418 device families available in 10L TDFN (3x3x0.8mm) package.

Pre and Post Summary Changes:

	Pre Change	Post Change	ange				
Assembly Site	Amkor Assembly & Test (Shanghai) Co., LTD. (ANAC)	Amkor Assembly & Test (Shanghai) Co., LTD. (ANAC)	Amkor Technology Philippines (P3/P4), INC. (ATP7)				

Wire Material	Au	Au	Au		
Die Attach Material	CRM-1085A	CRM-1085A	CRM-1085A		
Molding Compound Material	G631BQF	G631BQF	G631BQF		
Lead-Frame Material	C194	C194	C194		

Impacts to Datasheet: None

Change Impact: None

Reason for Change: To improve on-time delivery performance by qualifying ATP7 as an additional

assembly site.

Change Implementation Status: In Progress

Estimated Qualification Completion Date: March 2025

Note: Please be advised the qualification completion times may be extended because of unforeseen business conditions however implementation will not occur until after qualification has completed and a final PCN has been issued. The final PCN will include the qualification report and estimated first ship date. Also note that after the estimated first ship date guided in the final PCN customers may receive pre and post change parts.

Timetable Summary:

	October 2024					>	March 2025				
Work Week	40	41	42	43	44		10	11	12	13	14
Initial PCN Issue Date					Х						
Qual Report Availability											Х
Final PCN Issue Date											Х

Method to Identify Change: Traceability Code

Qualification Plan: Please open the attachments included with this PCN labeled as PCN_#_Qual_Plan.

Revision History: October 30, 2024: Issued initial notification.

Note: The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable product.

Attachments:

PCN_MAAN-27WMLJ297 Qual_Plan.pdf

Please contact your local **Microchip sales office** with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our **PCN home page** select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the **PCN FAQ** section.

If you wish to <u>change your PCN profile, including opt out,</u> please go to the **PCN home page** select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

MAAN-27WMLJ297 - CCB 7227 Initial Notice: Qualification of ATP7 as an additional assembly site for selected MCP16411, MCP16412, MCP16413, MCP16414, MCP16415, MCP16416, MCP16417 and MCP16418 device families available in 10L TDFN (3x3x0.8mm) package.

Affected Catalog Part Numbers (CPN)

MCP16411-I/MN

MCP16412-I/MN

MCP16413-I/MN

MCP16414-I/MN

MCP16411T-I/MN

MCP16412T-I/MN

MCP16413T-I/MN

MCP16414T-I/MN

MCP16415-I/MN

MCP16416-I/MN

MCP16417-I/MN

MCP16418-I/MN

MCP16415T-I/MN

MCP16416T-I/MN

MCP16417T-I/MN

MCP16418T-I/MN

Date: Tuesday, October 29, 2024



QUALIFICATION PLAN SUMMARY

PCN #: MAAN-27WMLJ297

Date:

October 24, 2024

Qualification of ATP7 as an additional assembly site for selected MCP16411, MCP16412, MCP16413, MCP16414, MCP16415, MCP16416, MCP16417 and MCP16418 device families available in 10L TDFN (3x3x0.8mm) package.

Purpose: Qualification of ATP7 as an additional assembly site for selected

MCP16411, MCP16412, MCP16413, MCP16414, MCP16415,

MCP16416, MCP16417 and MCP16418 device families available in 10L

TDFN (3x3x0.8mm) package.

CCB No.: 7227

	Assembly site	ATP7			
	BD Number	BD-002720-01			
	MP Code (MPC)	VA8A1TQAXA00			
Misc.	Part Number (CPN)	MCP16411T-I/MN			
<u>IVIISC.</u>	MSL information	MSL1, 260'C			
	Assembly Shipping Media (T/R, Tube/Tray)	Tube			
	Base Quantity Multiple (BQM)	120, 3300			
	Reliability Site	MTAI			
	Paddle size	75x106mils			
	Material	C194			
	DAP Surface Prep	Double Ring Ag			
	Treatment	Rough			
Lead-Frame	Process	Etch			
<u>Leau-Frairie</u>	Lead-lock	No			
	Part Number	101383221			
	Lead Plating	MatteSn			
	Strip Size	250x70			
	Strip Density	1224			
Bond Wire	Material	Au			
Die Attach	Part Number	CRM-1085A			
	Conductive	Yes			
<u>MC</u>	Part Number	G631BQF			
	Package Type	TDFN			
<u>PKG</u>	Pin/Ball Count	10			
	PKG width/size	3x3x0.8mm			

Test Name	Conditions	Sample Size	Min. Qty of Spares per Lot (should be properly marked)	Qty of Lots	Total Units	Fail Accept Qty	Est. Dur. Days	ATE Test Site	REL Test Site	Special Instructions
Standard Pb-free	J-STD-002D ; Perform 8 hour steam aging for Matte tin finish and	22	5	1	27	> 95% lead	5	MTAI	MTAI	
Solderability	1 hour steam aging for NiPdAu finish prior to testing.					coverage				
	Standard Pb-free: Matte tin/ NiPdAu finish, SAC solder, wetting temp 245°C for both SMD & through hole packages.									Standard Pb-free solderability is the requirement.
Backward Solderability	J-STD-002D ;Perform 8 hours steam aging for Matte tin finish and 1 hour steam aging for NiPdAu finish prior to testing.	22	5	1	27	> 95% lead coverage	5	MTAI	MTAI	SnPb solderability (backward solderability- SMD reflow soldering) is required for any plating related changes and highly recommended for other package BOM changes.
	Backward: Matte tin/ NiPdAu finish, SnPb solder, wetting temp 215°C for SMD.									
Wire Bond Pull - WBP	Mil. Std. 883-2011	5	0	1	5	0 fails after TC	5	ATP7	ATP7	30 bonds from a min. 5 devices.
Wire Bond Shear - WBS	CDF-AEC-Q100-001	5	0	1	5	0	5	ATP7	ATP7	30 bonds from a min. 5 devices.
Wire Sweep								ATP7	ATP7	Required for any reduction in wire bond thickness.
Physical Dimensions	Measure per JESD22 B100 and B108	10	0	3	30	0	5	ATP7	ATP7	
External Visual	Mil. Std. 883-2009/2010	All devices prior to submission for qualification testing	0	3	ALL	0	5	MTAI	MTAI	
Preconditioning - Required for	JESD22-A113. +150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow temperature	231	15	3	738	0	15	MTAI	MTAI	Spares should be properly identified. 77 parts from each lot to be used for HAST, uHAST, Temp Cycle test.
surface mount devices	per Jedec-STD-020E for package type; Electrical test pre and post stress at +25°C. MSL1. 260°C									77 paris from each for to be used for thost, if the fig. 1 emp cycle test.
HAST	JESD22-A110. +130°C/85% RH for 96 hours or 110°C/85%RH for 264 hours.	77	5	3	246	0	10	MTAI	MTAI	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
	Electrical test pre and post stress at +25°C and +85°C.									
UHAST	JESD22-A118. +130°C/85% RH for 96 hrs or +110°C/85% RH for 264 hrs.	77	5	3	246	0	10	MTAI	MTAI	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.
	Electrical test pre and post stress at +25°C									
Temp Cycle	JESD22-A10465°C to +150°C for 500 cycles. Electrical test pre and post stress at +85°C; 3 gram force WBP, on 5 devices from 1 lot, test following Temp Cycle stress.	77	5	3	246	0	15	MTAI	MTAI	Spares should be properly identified. Use the parts which have gone through Pre-conditioning.